

<b>Notice of References Cited</b>	Application/Control No. 10/568,420		Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner Sean P. Cullen, Ph.D.		Art Unit 1725	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0106564 A1	08-2002	Okawa et al.	429/221
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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**FOREIGN PATENT DOCUMENTS**

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